

PATENT ABSTRACTS OF JAPAN

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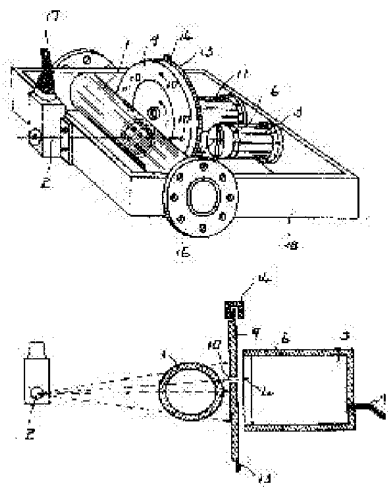
(21)Application number : **56-060601** (71)Applicant : **TOSHIBA CORP**
(22)Date of filing : **23.04.1981** (72)Inventor : **NARABAYASHI SUNAO**

(54) **RADIATION VOID FACTOR METER**

(57)Abstract:

PURPOSE: To measure the void factor of a double layer current in a quick and accurate way, by carrying out a radiation beam scan via plural slits provided on a rotary disk.

CONSTITUTION: A cylindrical measuring part 1 of a pipe in which a double phase current of a vapor phase like the high temperature and high pressure steam of a reactor, a boiler, etc. and a liquid phase like water, etc. is irradiated by an X-ray radiation beam given from a radiation source 2. The X-ray radiation beam corresponding to the void factor corresponding to the ratio between the vapor phase the liquid phase is detected by a radiation detector 3 through a number of slits 10 on a disk 9 which turns in a constant speed. In such constitution, the section of the part 1 is scanned by the X-ray radiation beam from the lower part to the part. Thus a local factor distribution is measured in a quick and accurate way. As a result, the section mean void factor can be assuredly decided even in the high-speed transient mode.



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